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Form PTO 1449 (Modified)		U.S. DEPARTMENT C PATENT AND TRAD	OF COMMERCE EMARK OFFICE	217374US2PCT	New US PCT application				
					based on PCT/JP00/03076				
LIST OF	REFE	RENCES CITED BY APF	PLICANT	Atsushi ITO, et al.					
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		DOCUMENT NUMBER	DATE	COUNTRY		TRANSLATION YES NO			
KN	AK	991052	04/05/00	EUROPE	 		,		
kN/	AL	991051	04/05/00	EUROPE					
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KN	AS	8-278766	10/22/96	JAPAN (with English abstract)				×	
KN	AT	7-140927	06/02/95	JAPAN (with English abstract)				×	
KN	AU	9-325736	12/16/97	JAPAN (with English abstract)				×	
kN	AV	8-212930	08/20/96	JAPAN (with English abstract)				×	
		OTHER RE	FERENCES (Including Author, Title, Date, Pertinen	t Pages, e	tc.)			
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